# MOSFET – Power, N-Channel, SUPERFET<sup>®</sup> III, Easy Drive 650 V, 6 A, 600 m $\Omega$

# FCPF600N65S3R0L-F154

## **Description**

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate. Consequently, SUPERFET III MOSFET Easy drive series helps manage EMI issues and allows for easier design implementation.

#### **Features**

- $700 \text{ V} @ \text{T}_{\text{J}} = 150^{\circ}\text{C}$
- Typ.  $R_{DS(on)} = 474 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q<sub>g</sub> = 11 nC)
- Low Effective Output Capacitance (Typ. C<sub>oss(eff.)</sub> = 127 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

#### **Applications**

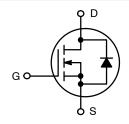
- Computing / Display Power Supplies
- Telecom / Server Power Supply
- Industrial Power Supplies
- Lighting / Charger / Adapter



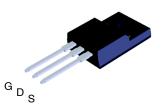
#### ON Semiconductor®

#### www.onsemi.com

V <sub>DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
650 V	600 mΩ @ 10 V	6 A

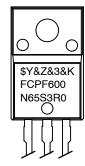


**N-Channel MOSFET** 



TO-220F Ultra Narrow Lead CASE 221BN

#### **MARKING DIAGRAM**



\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Numeric Date Code

&K = Lot Code

1

FCPF600N65S3R0 = Specific Device Code

#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 2 of this data sheet.

## ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25°C, Unless otherwise specified)

Symbol	Para	Value	Unit		
V <sub>DSS</sub>	Drain to Source Voltage		650	V	
V <sub>GSS</sub>	Gate to Source Voltage	DC	±30	V	
		AC (f > 1 Hz)	±30	V	
I <sub>D</sub>	Drain Current	Continuous (T <sub>C</sub> = 25°C)	6*	А	
		Continuous (T <sub>C</sub> = 100°C)	3.8*	1	
I <sub>DM</sub>	Drain Current	Pulsed (Note 1)	15*	А	
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		24	mJ	
I <sub>AS</sub>	Avalanche Current (Note 2)		1.6	А	
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		0.24	mJ	
dv/dt	MOSFET dv/dt		100	V/ns	
	Peak Diode Recovery dv/dt (Note 3)		20		
$P_{D}$	Power Dissipation	(T <sub>C</sub> = 25°C)	24	W	
		Derate Above 25°C	0.19	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 s		300	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.
\*Drain current limited by maximum junction temperature.

## THERMAL CHARACTERISTICS

Symbol	Parameter	FCPF600N65S3R0L	Unit
$R_{ hetaJC}$	Thermal Resistance, Junction to Case, Max.	5.29	°C/W
$R_{ hetaJA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	C/VV

## PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Packing Method	Reel Size	Tape Width	Quantity
FCPF600N65S3R0L	FCPF600N65S3R0	TO-220F	Tube	N/A	N/A	50 Units

<sup>1.</sup> Repetitive rating: pulse-width limited by maximum junction temperature. 
2.  $I_{AS} = 1.6 \text{ A}$ ,  $R_G = 25 \Omega$ , starting  $T_J = 25^{\circ}\text{C}$ . 
3.  $I_{SD} \le 3 \text{ A}$ , di/dt  $\le 200 \text{ A}/\mu\text{s}$ ,  $V_{DD} \le 400 \text{ V}$ , starting  $T_J = 25^{\circ}\text{C}$ .

# **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
OFF CHARACT	ERISTICS		•		•	
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1 mA, T <sub>J</sub> = 25°C	650	-	_	V
		V <sub>GS</sub> = 0 V, I <sub>D</sub> = 1 mA, T <sub>J</sub> = 150°C	700	-	-	V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 1 mA, Referenced to 25°C	-	0.66	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 650 V, V <sub>GS</sub> = 0 V	-	_	1	μΑ
		V <sub>DS</sub> = 520 V, T <sub>C</sub> = 125°C	-	0.3	-	
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±30 V, V <sub>DS</sub> = 0 V	-	_	±100	nA
ON CHARACTE	RISTICS					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 0.12 \text{ mA}$	2.5	-	4.5	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 3 A	-	474	600	mΩ
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 3 A	-	3.6	-	S
DYNAMIC CHA	RACTERISTICS					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 400 V, V <sub>GS</sub> = 0 V, f = 1 MHz	-	465	_	pF
C <sub>oss</sub>	Output Capacitance		-	10	-	pF
C <sub>oss(eff.)</sub>	Effective Output Capacitance	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V	-	127	-	pF
C <sub>oss(er.)</sub>	Energy Related Output Capacitance	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V	-	17	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V	V <sub>DS</sub> = 400 V, I <sub>D</sub> = 3 A, V <sub>GS</sub> = 10 V	-	11	-	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	(Note 4)	-	3	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		-	4.9	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	0.9	-	Ω
WITCHING CH	IARACTERISTICS					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 400 \text{ V}, I_D = 3 \text{ A},$	-	11	_	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V, R}_{g} = 4.7 \Omega$ (Note 4)	-	9	-	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		-	29	-	ns
t <sub>f</sub>	Turn-Off Fall Time		-	14	-	ns
SOURCE-DRAI	N DIODE CHARACTERISTICS					
I <sub>S</sub>	Maximum Continuous Source to Drain Diode Forward Current		-	-	6	Α
I <sub>SM</sub>	Maximum Pulsed Source to Drain Diode Forward Current		-	-	15	Α
$V_{SD}$	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 3 A	-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>DD</sub> = 400 V, I <sub>SD</sub> = 3 A,	-	198	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dl <sub>F</sub> /dt = 100 A/μs	_	1.6	-	μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of operating temperature typical characteristics.

#### TYPICAL PERFORMANCE CHARACTERISTICS

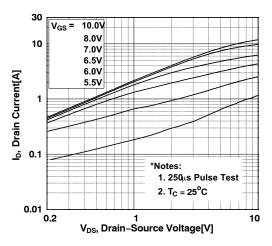


Figure 1. On-Region Characteristics

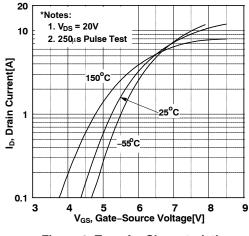


Figure 2. Transfer Characteristics

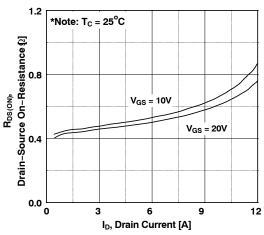


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

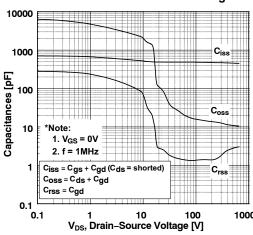


Figure 5. Capacitance Characteristics

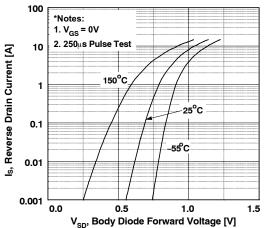


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and

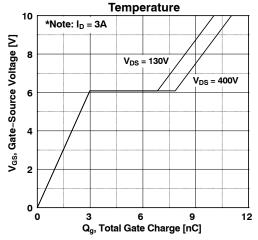


Figure 6. Gate Charge Characteristics

## TYPICAL PERFORMANCE CHARACTERISTICS (Continued)

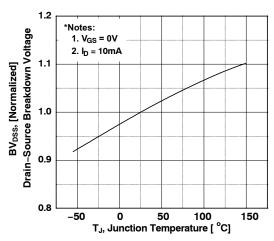


Figure 7. Breakdown Voltage Variation vs. Temperature

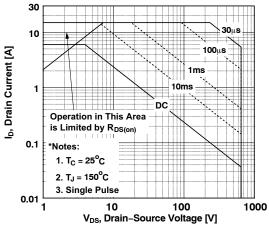


Figure 9. Maximum Safe Operating Area

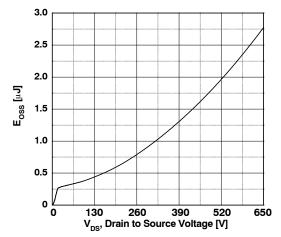


Figure 11. Eoss vs. Drain to Source Voltage

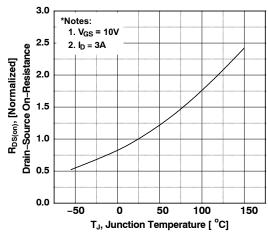


Figure 8. On-Resistance Variation vs. Temperature

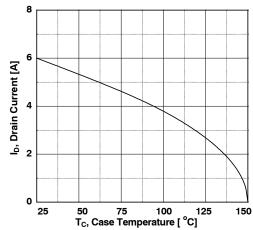


Figure 10. Maximum Drain Current vs.

Case Temperature

# TYPICAL PERFORMANCE CHARACTERISTICS (Continued)

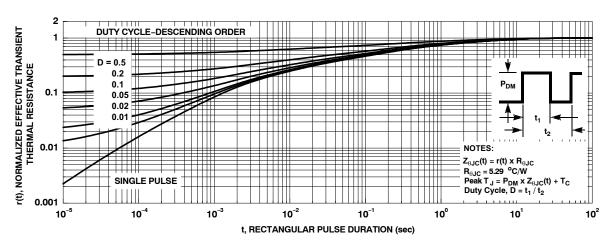


Figure 12. Transient Thermal Response Curve

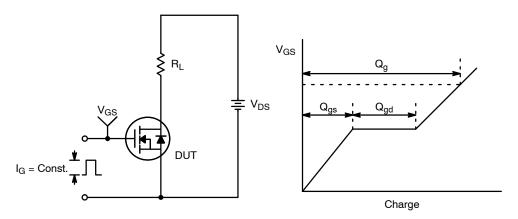


Figure 13. Gate Charge Test Circuit & Waveform

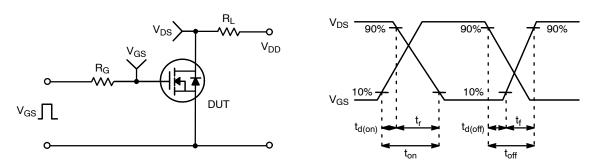


Figure 14. Resistive Switching Test Circuit & Waveforms

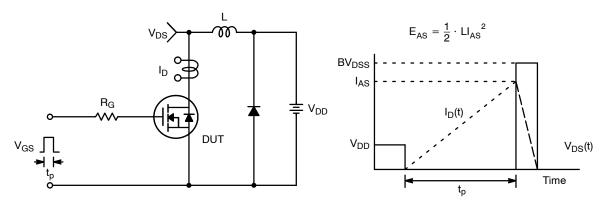


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

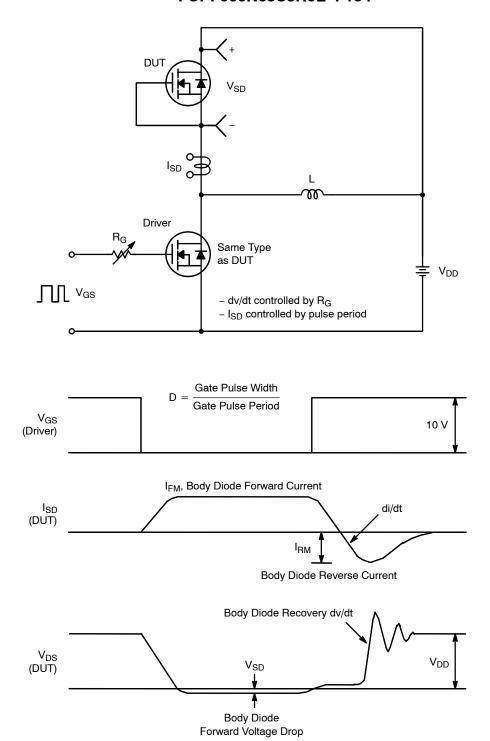


Figure 16. Peak Diode Recovery dt/dt Test Circuit & Waveforms

SUPERFET is a registered trademark of Semiconductor Components Industries, LLC (SCILLC) or its subsidiaries in the United States and/or other countries.

#### PACKAGE DIMENSIONS

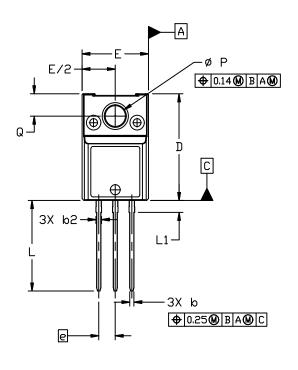
#### TO-220 FULLPACK, 3-LEAD

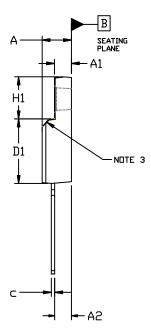
CASE 221BN **ISSUE O** 



#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETERS
- CONTOUR UNCONTROLLED IN THIS AREA. 3.
- DIMENSIONS EXCLUDE BURRS, MOLD FLASH, AND TIE BAR PROTRUSIONS.





	MILLIMETERS				
DIM	MIN.	N□M.	MAX.		
Α	4.60	4.70	4.80		
A1	2.50	2.60	2.70		
A2	2.47	2.57	2.67		
b	0.56	0.63	0.69		
β2			0.90		
C	0.46	0.53	0.59		
D	15.80	16.00	16.20		
D1	9.58	9.68	9.78		
Ε	10.00	10.20	10.40		
е	2.54 BSC				
H1	6.32 REF				
L	13.45	13.60	13.75		
L1	1.70	1.80	1.90		
Р	3.00	3.10	3.20		
Q	3.25	3.35	3,45		

ON Semiconductor and (III) are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability. arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that ON Semiconductor was negligent regarding the design or manufacture of the part. ON Semiconductor is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

#### **PUBLICATION ORDERING INFORMATION**

LITERATURE FULFILLMENT: Email Requests to: orderlit@onsemi.com

ON Semiconductor Website: www.onsemi.com

TECHNICAL SUPPORT North American Technical Support: Voice Mail: 1 800-282-9855 Toll Free USA/Canada

Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative